	BLE STANI	JAKD			letopace.				
	OPERATING TEMPERATUR	E RANGE	-55 °C TO 85	°C (1)	STORAGE TEMPERAT	TURE RANGE	-10 °C TO 60	C (2)	
RATING	VOLTAGE		100 V AC		STORAGE RANGE		40 % TO 70	% <sup>(2</sup>	2)
	13217.02			(2)	OPERATIN	G HUMIDITY			
	CURRENT		0.5 A (SIGNAL CONTA	RANGE		RELATIVE HUMIDITY	85%	max	
			3 A (MF CONTACT)			(NOT DEWED)			
			SPEC	IFICAT	IONS				
	TEM		TEST METHOD			REQ	UIREMENTS	QT	Α
CONSTR		<u> </u>							
MARKING		VISUALLY AND BY MEASURING INSTRUMENT.  CONFIRMED VISUALLY.			. ACCOI	RDING TO I	DRAWING.	×	>
	C CHARAC								<u> </u>
	RESISTANCE		) mA(DC OR 1000Hz)		SIGNA	L CONTAC	T : 90 m Ω MAX.	Τ×	Τ-
		(					: 30 m Ω MAX.		
INSULATION RESISTANCE		250 V DC.				1000 MΩN		×	_
VOLTAGE PROOF		300 V AC FOR 1 min.			NO FL	ASHOVER (	OR BREAKDOWN.	×	_
	ICAL CHAR							Ι×	
INSERTION AND WITHDRAWAL FORCES		MEASURED BY APPLICABLE CONNECTOR.				INSERTION FORCE: 80 N MAX. WITHDRAWAL FORCE: 8 N MIN.			-
MECHANICAL FORCES		500 TIMES INSERTIONS AND EXTRACTIONS.				NTACT RES		×	<u> </u>
OPERATION					1 -	SIGNAL CONTACT : 100 m Ω MAX.  MF CONTACT : 40 m Ω MAX.			
					<b>I</b>				
						DAMAGE, ( PARTS.	CRACK AND LOOSENESS		
VIBRATION		FREQUENCY 10 TO 55 TO 10Hz, APPROX 5min					AL DISCONTINUITY OF	×	+-
		SINGLE A	AMPLITUDE : 0.75 mm, 10 C		1 μι				
		FOR 3 DIRECTIONS.					CRACK AND LOOSENESS		
SHOCK		490 m/s <sup>2</sup> , DURATION OF PULSE 11 ms AT 3 TIMES FOR 3 DIRECTIONS.				PARTS.		×	-
FNVIRON	IMENTAL C			IONS.				l	1
DAMP HEAT			DAT 40±2 °C, 90 ~ 95	5 %. 96 h	n. ① CO	NTACT RES	SISTANCE:	×	Τ-
(STEADY STATE)					- 1	NAL CONT	ACT : 100 m Ω MAX.		
RAPID CHANGE OF TEMPERATURE		TEMPERATURE -55 $\rightarrow$ +85 °C TIME 30 $\rightarrow$ 30 min. UNDER 5 CYCLES.				CONTACT		×	-
					(2) INS	SULATION R	RESISTANCE :1000 MΩ MIN.		
			TION TIME TO CHAMBER:WITH	HIN 2∼3 MIN	) 3 NO	DAMAGE.	CRACK AND LOOSENESS		
		(112200711	TOTAL TO STIP MADELATIVITY			PARTS.			
SULFUR DIOXIDE		EXPOSED AT 25±2°C, 75±5%RH, 25 PPM FOR			NO HE	AVY CORR	OSION.	×	-
		96 h.  /TEST ST	ANDARD: JIS C 60068)						
		(1201 01	71112711125. 010 0 00000)						
	NT DE	ESCRIPTION	ON OF REVISIONS		ESIGNED		CHECKED	DATE	
COUN									
		REMARKS (1) INCLUDE TEMPERATURE RISE CAUSED BY CURRENT-CARRYING.				APPROVE	D HS. OKAWA	13. 03. 2	
<b>∕</b> 0∖						CHECKED KI. HIROK			
<b>∕</b> 0∖	(2) "STORAGE" ME	ANS A LON	G-TERM STORAGE STATE  JCT BEFORE ASSEMBLY TO PCB	3			NI. IIINOKAWA	13.0	<u>3.</u> 2
<b>1</b>	(2) "STORAGE" ME FOR THE UNUS (3) THE RATED CU	EANS A LONG SED PRODU JRRENT APF	JCT BEFORE ASSEMBLY TO PCB PLIES TO PER CONTACT.			DESIGNE	<u> </u>	13. C	
REMARKS	(2) "STORAGE" ME FOR THE UNU: (3) THE RATED CU APPLY 0.4A WH	EANS A LON SED PRODU JRRENT APF HEN ALL TH	JCT BEFORE ASSEMBLY TO PCB PLIES TO PER CONTACT. IE CONTACTS ARE USED FOR CU		RYING.		D TH. SANO	13.0	3. 2
REMARKS Unless of	(2) "STORAGE" ME FOR THE UNU: (3) THE RATED CL APPLY 0.4A WI nerwise specif	EANS A LONI SED PRODU JRRENT APF HEN ALL TH fied, refer	UCT BEFORE ASSEMBLY TO PCB PLIES TO PER CONTACT. IE CONTACTS ARE USED FOR CU r to JIS-C-5402.	URRENT CAR		DRAWN	TH. SANO TH. SANO	13. C	3. 2
Unless oth	(2) "STORAGE" ME FOR THE UNUS (3) THE RATED CL APPLY 0.4A WI DERWISE SPECIT Ualification Test	EANS A LONI SED PRODL JRRENT APF HEN ALL TH fied, refer t AT:Assu	JCT BEFORE ASSEMBLY TO PCB PLIES TO PER CONTACT. IE CONTACTS ARE USED FOR CU r to JIS-C-5402. urance Test X:Applicable Tes	URRENT CAR	DRAWIN	DRAWN	TH. SANO TH. SANO ELC4-349366	13. 0 13. 0 - <b>00</b>	3. 2
REMARKS Unless of	(2) "STORAGE" ME FOR THE UNUS (3) THE RATED CL APPLY 0.4A WI nerwise specification Test	EANS A LONING SED PRODU PRENT APPHEN ALL THE FIELD, reference of the AT:Assument of the A	UCT BEFORE ASSEMBLY TO PCB PLIES TO PER CONTACT. IE CONTACTS ARE USED FOR CU r to JIS-C-5402.	urrent car		DRAWN	TH. SANO TH. SANO ELC4-349366 FX18-140PS-0. 8H15	13. 0 13. 0 -00	3. 2